

R&D of MCP-PMTs

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XIOPM MCP-PMTs





XI'AN INSTITUTE OF OPTICS AND PRECISION MECHANICS CHINESE ACADEMY OF SCIENCES

- Participated in the development of 20-inch MCP-PMT and 3 inch dynode-PMT for JUNO from 2012-2016
- Developed Gated MCP-PMT for DCI laser fusion experiment
- Developed MCP-PMT with high current output
- Developing Long-life multi-anode MCP-PMT for STCF





20 inch MCP-PMT



Gated MCP-PMT

Large current MCP-PMT



Long-life MCP-maPMT₂

Super Tam Charm Facility (STCF) in China





- Potential for upgrade to increase luminosity and realize polarized beam
- Site: 1 km², Hefei's suburban "Future Big Science City"

STCF PID (DTOF)





MCP-PMT requirements

- 4x4 anodes
- Gain > 1E6
- TTS < 100 ps

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- QE > 20%
- Lifetime > ten years (IAC > 10C/cm2)
- High rate capability
 - Image: Side View
 Side View
 Front View

DTOF: DIRC-like TOF

microchannel plate



Conventional MCP

- Made of lead glass
- Collection efficiency ~60%
- Gain from lead glass
- Maximum SEE yield \sim 3



□ ALD-MCP based on lead glass □ ALD-MCP based on borosilicate

nichrome

glass wall

high SEY film

- Coating Al2O3/MgO on the lead glass MCP input surface and channel
- Maximum SEE yield over 4
- Gain mainly from ALD-layer
- Collection efficiency improved to ~100%
- Lifetime extended

photoelectrons

secondary

electrons

MCP channel

glass

- Lead free
- ALD coating resistive layer and emissive layer
- Gain resulted from ALD-Layer
- Maximum SEE over 4
- Lifetime extended







A. Lehmann et al., GSI scientific report 2022D01:10.15120/GS1-2023-00462



Gain







Factors affecting the lifetime of MCP-PMT?

ALD layer thickness and scrubbing amount

- MCPs with and without ALD layer
- ALD layer of 1 nm, 4.5 nm, 6nm thickness
- MCP scrubbed amount of 0.43~0.75 uA-h/cm²
- Operated at gain of 5e5~1e6
- Light source
 - LED driven by a pulse generator
 - 10 ns pulse width
 - 405 nm wavelength



$$C = \sum \overline{q} \cdot t \cdot f$$





ALD film thickness effect

Lifetime@ 6 nm > 4.5 nm > 1nm > none

Scrubbing amount effect

1.0

Lifetime@ 0.75 uA-h/cm² > 0.52 uA-h/cm² > 0.43 uA-h/cm²

IAC over 11 C/cm2



Table 2. IAC at 50% anode output degradation for the MCP-PMTs.

ID	Thickness of the ALD-layer (nm)	Electron scrubbing dosage $(\mu \mathbf{A} \cdot \mathbf{h}/\mathbf{cm}^2)$	IAC at 50% degradation (mC/cm ²)
25-221231	1	0.43	117
25 - 230630	None	0.43	26
25 - 230722	1	0.52	230
25 - 230727	1	0.75	373
25 - 230825	1	0.75	373
25 - 231109	4.5	0.75	8800
25 - 231127	6	0.75	> 11,000





Performances before and after lifetime tests

25-231127 with IAC over 11 C/cm2

none degradation on photocathode and MCP





Performances before and after lifetime tests

25-221231 \cdot # 25-230630 \cdot # 25-230722 with IACs less than 0.56C/cm2

- Degradations on photocathode and MCP
- QE decreases more at longer wavelengths

Table 2.	IAC at	50% anode	output	degradation	for	the	MCP-	PMTs.
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Rate capability



measurement setup

- Single-anode MCP-PMTs
- LD driven by a pulse generator
- 10 ns pulse width
- ~3500 photons/cm2 /pulse







ALD film effect

- MCP-PMTs with different thickness of ALD film operated at 1E5 gain
- illuminated by LD at rates of 10 Hz \sim 500 kHz \sim 10 Hz for 84 seconds to be saturated



Illumination rate effect

- The greater the degree of saturation, the slower the recovery
- Super linearity is worse at higher rate for none-ALD MCP





Super linearity for none-ALD MCP

Super linearity is worse for stronger illumination



400ns,1.4V

800ns,1.4V











Saturation duration effect

- The longer the saturation duration, the slower the recovery.
- When the saturation duration exceeds a certain value (e.g. 42s), the recovery behavior no longer changes.



Supply voltage effect

- Higher supply voltage seems better for recovery for the ALD-MCP
- Super linearity can be less for higher HV





Magnetic fields effects



How magnetic fields decrease gain

Electron trajectories in the MCP channel under the magnetic fields are simulated with CST program.

- Electrons move in a spiral under the influence of a magnetic field.
- This causes the electrons to be accelerated over a shorter distance.
- Reduction in the energy of electrons hitting the microchannel plate.



Magnetic fields effects



Reduced number of secondary electrons produced due to lower impact energy



Magnetic fields effects



- The number of electron collisions in the microchannel increases and then decreases.
- Gain is the result of the combined effect of the number of collisions and collision energy.



Gating function



MCP-PMT with gating function is developed to detect a weak neutron signal in

the presence of strong gamma noise.

A gating electrode was incorporated between the cathode and the microchannel plate to control the voltage between the cathode and the gating electrode.









Thank you for your attention !